

The GreenMOS[®] high voltage MOSFET utilizes charge balance technology to achieve outstanding low on-resistance and lower gate charge. It is engineered to minimize conduction loss, provide superior switching performance and robust avalanche capability.

The GreenMOS[®] Generic series is optimized for extreme switching performance to minimize switching loss. It is tailored for high power density applications to meet the highest efficiency standards.

GreenMOS[®]

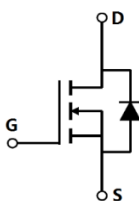
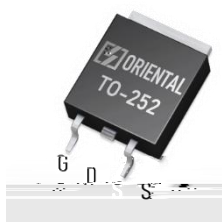


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Parameter	Value	Unit
$V_{DS, min} @ T_{j(max)}$	700	V
$I_{D, pulse}$	13.5	A
$R_{DS(ON), max} @ V_{GS}=10V$	900	
Q_g	7.1	nC

Product Name	Package	Marking
OSG65R900DTF	TO252	OSG65R900DT



Absolute Maximum Ratings at $T_j=25$ unless otherwise noted

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	650	V
Gate-source voltage	V_{GS}	± 30	V
Continuous drain current ¹⁾ , $T_C=25$ °C	I_D	4.5	A
Continuous drain current ¹⁾ , $T_C=100$ °C		2.8	
Pulsed drain current ²⁾ , $T_C=25$ °C	$I_{D, pulse}$	13.5	A
Continuous diode forward current ¹⁾ , $T_C=25$ °C	I_S	4.5	A
Diode pulsed current ²⁾ , $T_C=25$ °C	$I_{S, pulse}$	13.5	A
Power dissipation ³⁾ , $T_C=25$ °C	P_D	32	W
Single pulsed avalanche energy ⁵⁾	E_{AS}	50	mJ
MOSFET dv/dt ruggedness, V_{DS}	dv/dt	50	V/ns
Reverse diode dv/dt, V_{DS} & I_{SD}	dv/dt	15	V/ns
Operation and storage temperature	T_{stg}, T_j	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal resistance, junction-case	R	3.9	°C/W
Thermal resistance, junction-ambient ⁴⁾	R	62	°C/W

Electrical Characteristics at $T_j=25$ unless otherwise specified

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Drain-source breakdown voltage	BV_{DSS}	650			V	$V_{GS}=0$ V, $I_D=250$ A
		700				$V_{GS}=0$ V, I_D , $T_j=150$ °C
Gate threshold voltage	$V_{GS(th)}$	2.9		3.9	V	$V_{DS}=V_{GS}$, $I_D=250$ A
Drain-source on-state resistance	$R_{DS(ON)}$		0.75	0.9		$V_{GS}=10$ V, $I_D=2$ A
			1.75			$V_{GS}=10$ V, $I_D=2$ A, $T_j=150$ °C
Gate-source leakage current	I_{GSS}			100	nA	$V_{GS}=30$ V
				-100		$V_{GS}=-30$ V
Drain-source leakage current	I_{DSS}			1	A	$V_{DS}=650$ V, $V_{GS}=0$ V

Dynamic Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Input capacitance	C_{iss}		324.1		pF	$V_{GS}=0\text{ V}$, $V_{DS}=50\text{ V}$, 00 kHz
Output capacitance	C_{oss}		30.1		pF	
Reverse transfer capacitance	C_{rss}		1.6		pF	
Turn-on delay time	$t_{d(on)}$		22.8		ns	$V_{GS}=10\text{ V}$, $V_{DS}=400\text{ V}$, R_G & $I_D=2\text{ A}$
Rise time	t_r		11.5		ns	
Turn-off delay time	$t_{d(off)}$		48.7		ns	
Fall time	t_f		14.9		ns	

Gate Charge Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Total gate charge	Q_g		7.1		nC	$V_{GS}=10\text{ V}$, $V_{DS}=400\text{ V}$, $I_D=2\text{ A}$
Gate-source charge	Q_{gs}		1.5		nC	
Gate-drain charge	Q_{gd}		3.5		nC	
Gate plateau voltage	$V_{plateau}$		5.8		V	

Body Diode Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Diode forward voltage	V_{SD}			1.3	V	$I_S=4.5\text{ A}$, $V_{GS}=0\text{ V}$
Reverse recovery time	t_{rr}		147		ns	$I_S=2\text{ A}$,))
Reverse recovery charge	Q_{rr}		0.92		C	
Peak reverse recovery current	I_{rrm}		12.4		A	

Note

- 1) Calculated continuous current based on maximum allowable junction temperature.
- 2) Repetitive rating; pulse width limited by max. junction temperature.
- 3) P_d is based on max. junction temperature, using junction-case thermal resistance.
- 4) The value of $R_{\theta j-c}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_a=25\text{ }^\circ\text{C}$.
- 5) $V_{DD}=100\text{ V}$, $V_{GS}=10\text{ V}$, $L=60\text{ mH}$, starting $T_j=25\text{ }^\circ\text{C}$.

Electrical Characteristics Diagrams

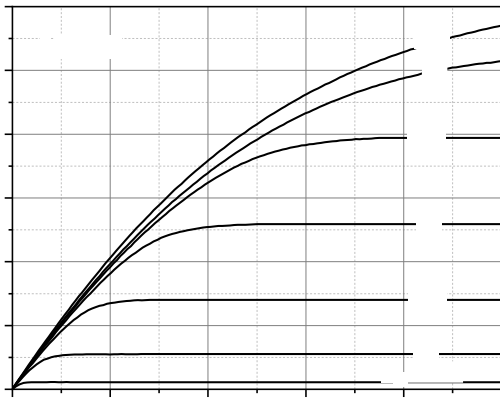


Figure 1. Typ. output characteristics

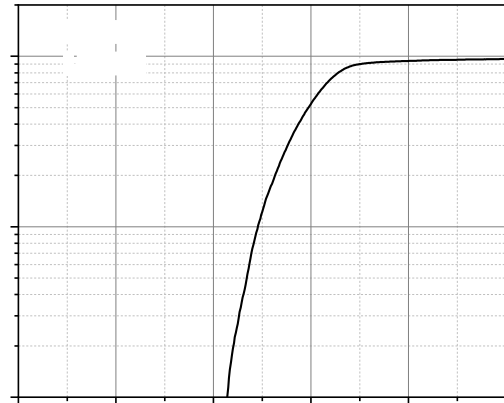


Figure 2. Typ. transfer characteristics

Figure 3. Typ. capacitances

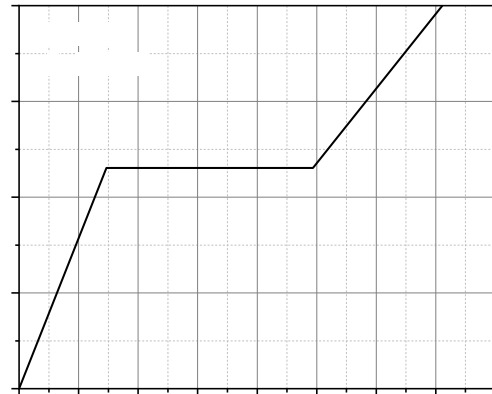


Figure 4. Typ. gate charge

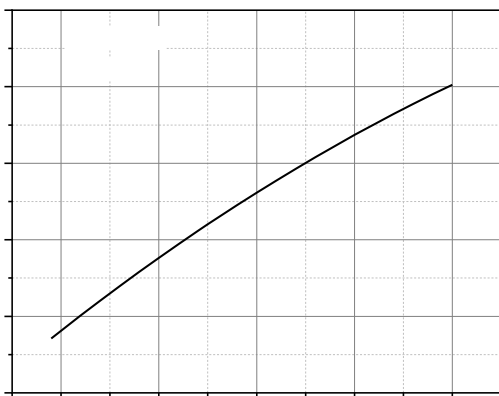


Figure 5. Drain-source breakdown voltage

Figure 6. Drain-source on-state resistance

<p>Figure 7. Threshold voltage</p>	<p>Figure 8. Forward characteristic of body diode</p>
<p>Figure 9. Drain-source on-state resistance</p>	<p>Figure 10. Drain current</p>

Figure 12. transient thermal impedance

Test circuits and waveforms

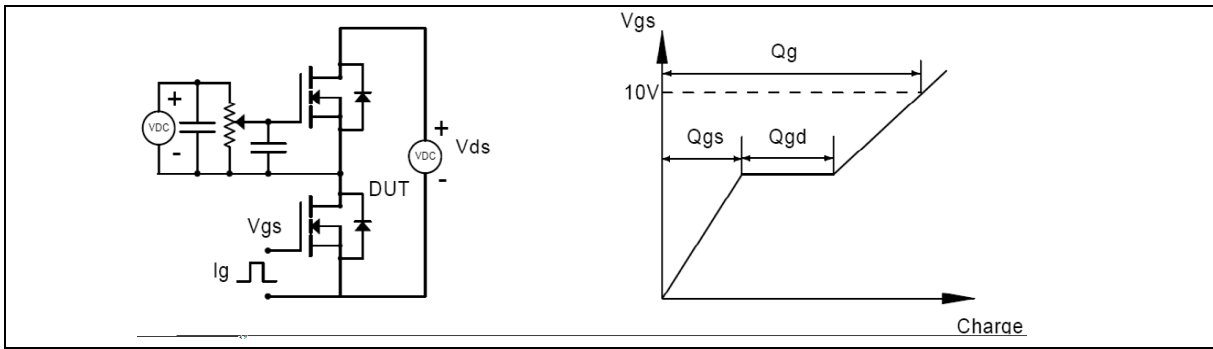


Figure 1. Gate charge test circuit & waveform



Figure 2. Switching time test circuit & waveforms

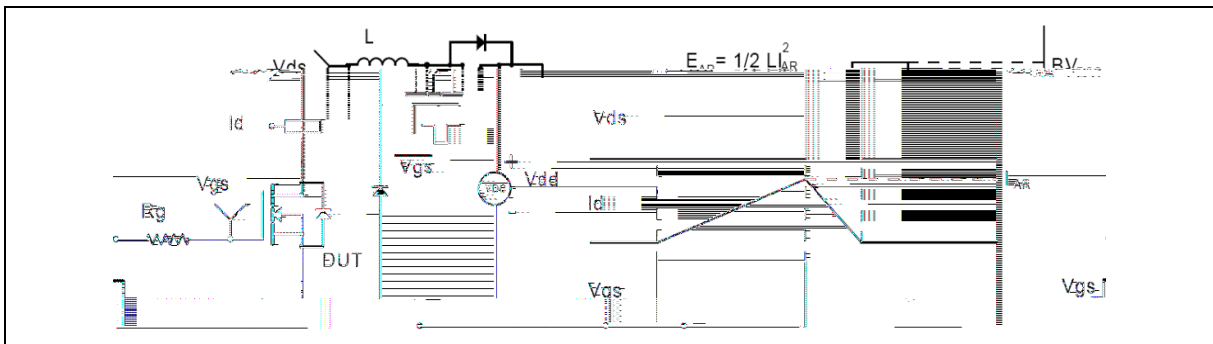


Figure 3. Unclamped inductive switching (UIS) test circuit & waveforms

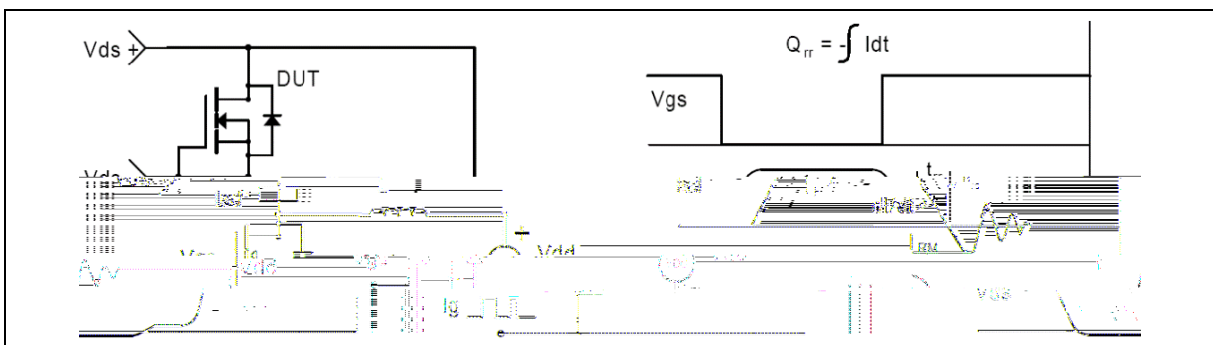
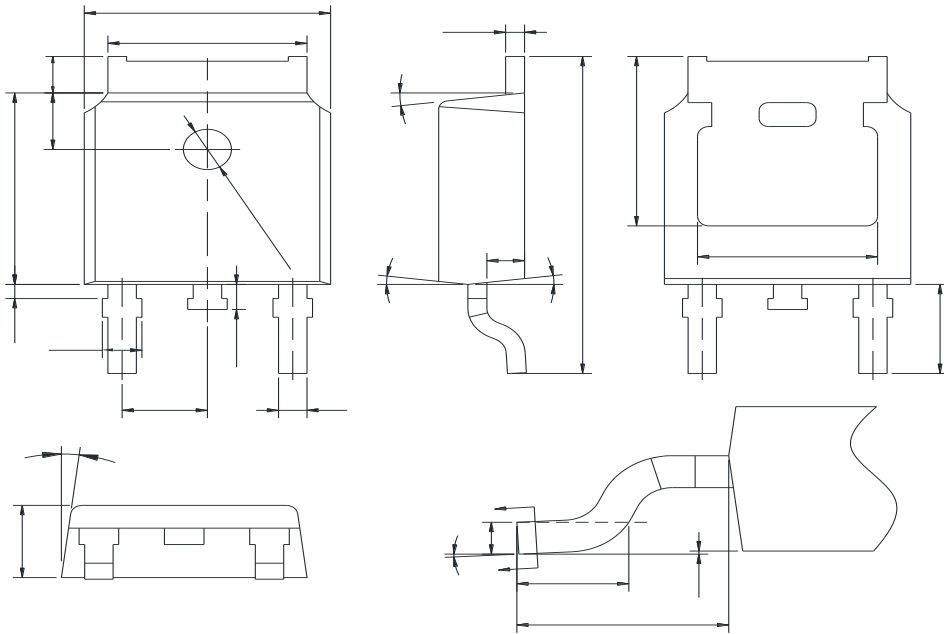


Figure 4. Diode reverse recovery test circuit & waveforms

Package Information



Symbol	mm		
	Min	Nom	Max
A	2.20	2.30	2.38
A1	0.00	-	0.10
A2	0.90	1.01	1.10
b	0.72	-	0.85
b1	0.71	0.76	0.81
b2	0.72	-	0.90
b3	5.13	5.33	5.46
c	0.47	-	0.60
c1	0.46	0.51	0.56
c2	0.47	-	0.60
D	6.00	6.10	6.20
D1	5.25	-	-
E	6.50	6.60	6.70
E1	4.70	-	-
e	2.186	2.286	2.386
H	9.80	10.10	10.40
L	1.40	1.50	1.70
L1	2.90REF		
L2	0.508BSC		
L3	0.90	-	1.25
L4	0.60	0.80	1.00
L5	0.15	-	0.75
L6	1.80REF		
	0	-	

Version 1: TO252-J package outline dimension

